Unit: mm

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSIV)

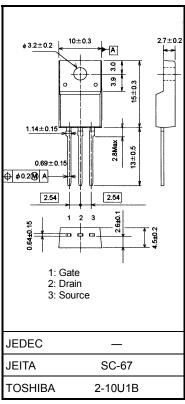
# 2SK3565

### **Switching Regulator Applications**

- Low drain-source ON resistance: RDS (ON) =  $2.0 \Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 4.5 \text{ S (typ.)}$
- Low leakage current: IDSS = 100  $\,\mu\,\mathrm{A}$  (VDS = 720 V)
- Enhancement mode:  $V_{th} = 2.0 \sim 4.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$

### Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	900	V	
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )		$V_{DGR}$	900	٧	
Gate-source voltage		V <sub>GSS</sub>	±30	V	
Drain current	DC (Note 1)	I <sub>D</sub>	5	А	
	Pulse (t = 1 ms) (Note 1)	I <sub>DP</sub>	15		
Drain power dissipation (Tc = 25°C)		PD	45	W	
Single pulse avalanche energy (Note 2)		E <sub>AS</sub>	595	mJ	
Avalanche current		I <sub>AR</sub>	5	Α	
Repetitive avalanche energy (Note 3)		E <sub>AR</sub>	4.5	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	



Weight: 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **Thermal Characteristics**

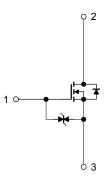
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	2.78	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	62.5	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2:  $V_{DD} = 90 \text{ V}$ ,  $T_{ch} = 25^{\circ}\text{C}(\text{Initial})$ , L = 43.6 mH,  $I_{AR} = 5.0 \text{ A}$ ,  $R_G = 25 \Omega$ 

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Please handle with caution.





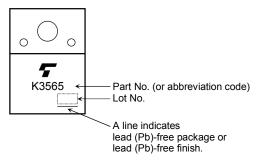
# Electrical Characteristics (Ta = 25°C)

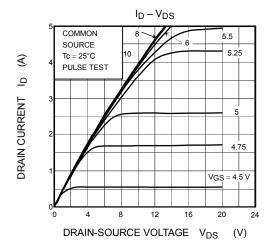
Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I <sub>GSS</sub>	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μА
Gate-source brea	akdown voltage	V (BR) GSS	$I_G = \pm 10 \mu A, V_{DS} = 0 V$	±30	_	_	V
Drain cut-off curr	ent	I <sub>DSS</sub>	V <sub>DS</sub> = 720 V, V <sub>GS</sub> = 0 V		_	100	μА
Drain-source bre	akdown voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	900	_	_	٧
Gate threshold vo	oltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	2.0	_	4.0	٧
Drain-source ON	resistance	R <sub>DS</sub> (ON)	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 3 A		2.0	2.5	Ω
Forward transfer	admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 3 A	2.0	4.5	_	S
Input capacitance	•	C <sub>iss</sub>			1150	_	
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	20	_	pF
Output capacitance		Coss			100	_	
Switching time	Rise time	t <sub>r</sub>	$V_{GS}$ $V_{DD} \simeq 200 \text{ V}$ $V_{DD} \simeq 200 \text{ V}$	_	30	_	
	Turn-on time	t <sub>on</sub>		_	70	_	
	Fall time	t <sub>f</sub>		_	60	_	ns
	Turn-off time	t <sub>off</sub>	Duty ≦ 1%, t <sub>W</sub> = 10 μs	_	170	_	
Total gate charge		Qg		_	28	_	
Gate-source charge		Qgs	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 5 \text{ A}$	_	17	_	nC
Gate-drain charge		Q <sub>gd</sub>			11	_	

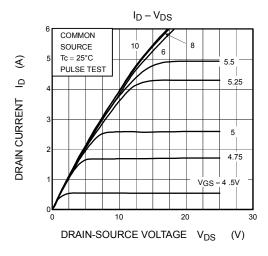
# Source-Drain Ratings and Characteristics (Ta = 25°C)

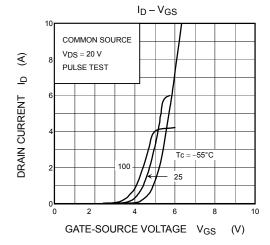
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	_	5	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	15	Α
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 5 A, V <sub>GS</sub> = 0 V	_	_	-1.7	V
Reverse recovery time	t <sub>rr</sub>	$I_{DR} = 5 \text{ A}, V_{GS} = 0 \text{ V},$	_	900	_	ns
Reverse recovery charge	Q <sub>rr</sub>	dI <sub>DR</sub> /dt = 100 A/μs	_	5.4	_	μС

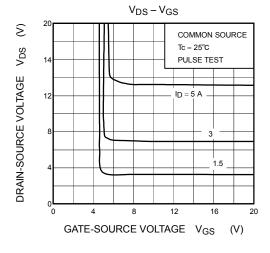
## Marking

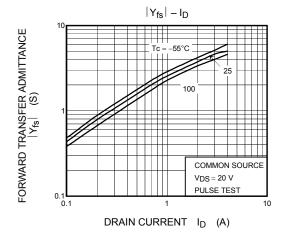


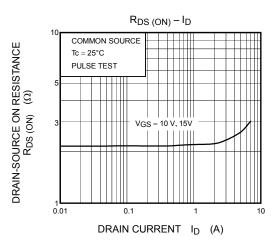


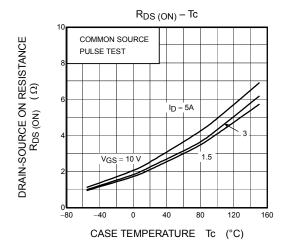


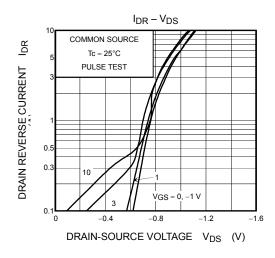


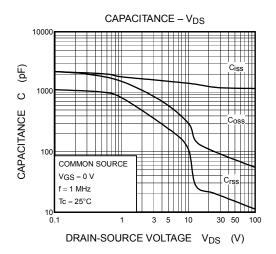


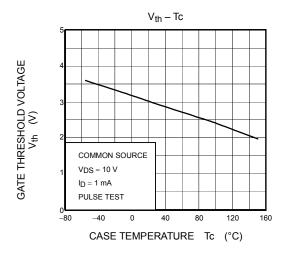


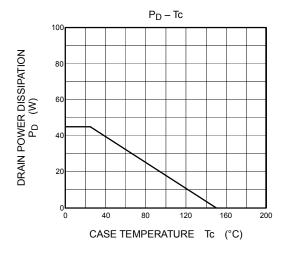


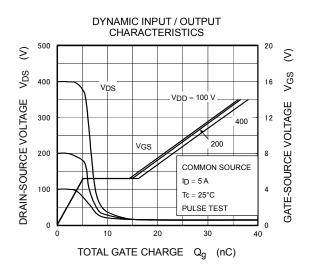




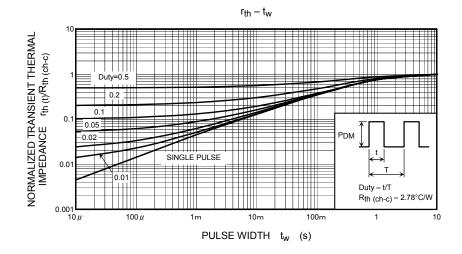


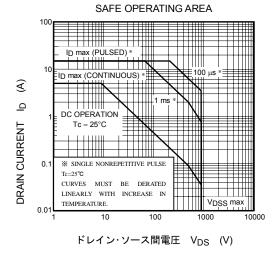


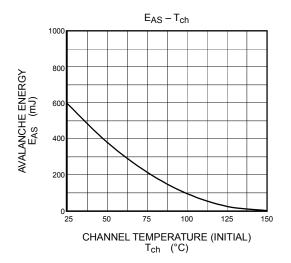


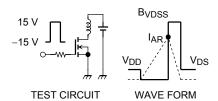


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$$\begin{aligned} R_G &= 25~\Omega \\ V_{DD} &= 90~V,~L = 43.6 mH \end{aligned}$$

$$\mathsf{E}_{AS} = \frac{1}{2} \cdot L \cdot l^2 \cdot \left( \frac{\mathsf{BVDSS}}{\mathsf{BVDSS} - \mathsf{VDD}} \right)$$

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